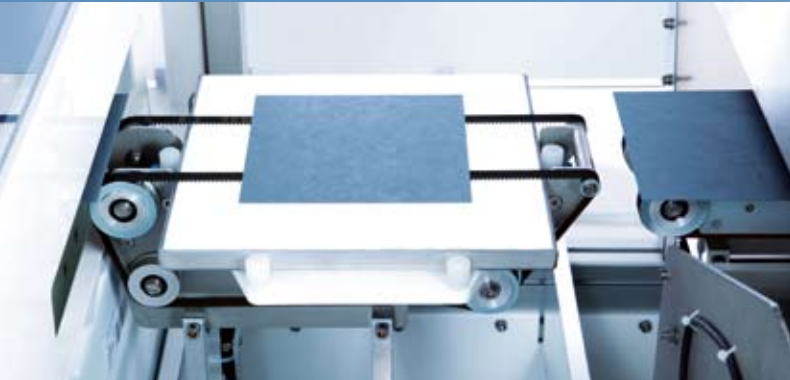


# SOLAR QCheck

R|E|N|A|.



## Quality Inspection System

Measuring, checking, sorting - RENA QCheck enables the classification of all wafers and cells. The modular system allows the integration of a variety of measuring systems. The resulting sorter module can be laid out as desired.

### Areas of application

- Applicable to all wafer and cell production sequences

### Features and benefits

- Modular design for individual configuration with measuring systems: thickness, TTV, bow, resistivity, lifetime, surface inspection, topology and geometry, multicrystallinity and micro crack detection
- Integration of customer defined measuring systems or industry standard measuring systems
- Arbitrary number of buffering classification stacks
- Each stack buffer has a capacity of minimum 300 wafers/quality class
- High throughput
- Small footprint
- User-friendly software interface, e.g. online help function

#### Optional:

- Connection to MES





Measuring systems for:  
micro crack detection,  
thickness, TTV, bow



Sorter module with  
stack buffer

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Front view QCheck

## Technical Data QCheck

Dimensions	• Depending on module combination (for 5 lane standard system) min. 1400 x 1500 x 2350 mm, max. 3500 x 1500 x 2350 mm (length x width x height)	
Wafer size	• 125 and 156 mm	
Optional	• 210 mm	
Geometry	• square or pseudo square	
Thickness	> 160 µm	
Breakage rate	< 0.05 %	
Throughput	3600 wafers/h netto	
Uptime	> 98 %	
Media consumption	• Compressed air	approx. 30 l/h
	• Electricity	200 - 400 V AC + 5 % 3Ph + N + PE 50 Hz < 32 A